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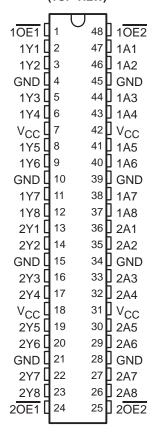
- Members of the Texas Instruments Widebus™ Family
- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Inputs Are TTL-Voltage Compatible
- Distributed V_{CC} and GND Pins Minimize High-Speed Switching Noise
- Flow-Through Architecture Optimizes PCB Layout
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds 2000 V Per MIL-STD-883, Method 3015; Exceeds 200 V Using Machine Model (C = 200 pF, R = 0)
- Package Options Include Plastic Shrink Small-Outline (DL), Thin Shrink Small-Outline (DGG), and Thin Very Small-Outline (DGV) Packages and 380-mil Fine-Pitch Ceramic Flat (WD) Package Using 25-mil Center-to-Center Spacings

description

These 16-bit buffers and bus drivers provide a high-performance bus interface for wide data paths.

The 3-state control gate is a 2-input AND gate with active-low inputs so that if either output-enable (OE1 or OE2) input is high, all corresponding outputs are in the high-impedance state.

SN54AHCT16540 . . . WD PACKAGE SN74AHCT16540 . . . DGG, DGV, OR DL PACKAGE (TOP VIEW)



To ensure the high-impedance state during power up or power down, \overline{OE} should be tied to V_{CC} through a pullup resistor; the minimum value of the resistor is determined by the current-sinking capability of the driver.

The SN54AHCT16540 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74AHCT16540 is characterized for operation from –40°C to 85°C.

FUNCTION TABLE (each 8-bit buffer/driver)

	OUTPUT		
OE1	OE2	Α	Y
L	L	L	Н
L	L	Н	L
Н	X	Χ	Z
Х	Н	Χ	Z

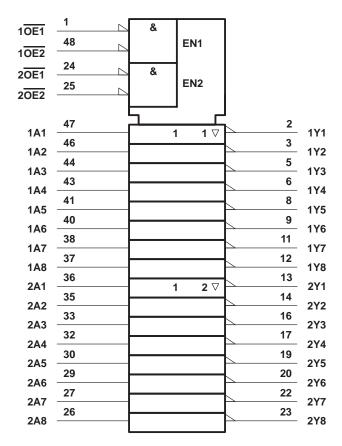


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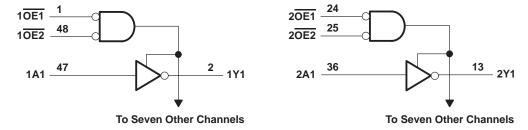


logic symbol[†]



[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage range, V _{CC}	–0.5 V to 7 V
Input voltage range, V _I (see Note 1)	–0.5 V to 7 V
Output voltage range, VO (see Note 1)	$-0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, I _{IK} (V _I < 0)	
Output clamp current, I _{OK} (V _O < 0 or V _O > V _{CC})	±20 mA
Continuous output current, I_O ($V_O = 0$ to V_{CC})	±25 mA
Continuous current through each V _{CC} or GND	±75 mA
Package thermal impedance, θ _{JA} (see Note 2): DGG package	70°C/W
DGV package	58°C/W
DL package	63°C/W
Storage temperature range, T _{Stg}	–65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

2. The package thermal impedance is calculated in accordance with JESD 51.

recommended operating conditions (see Note 3)

		SN54AHC	T16540	SN74AHC	UNIT	
		MIN	MAX	MIN	MAX	UNII
Vcc	Supply voltage	4.5	5.5	4.5	5.5	V
VIH	High-level input voltage	2	2	2		V
VIL	Low-level input voltage		0.8		0.8	V
٧ _I	Input voltage	0	5.5	0	5.5	V
Vo	Output voltage	0	Vcc	0	Vcc	V
loh	High-level output current	2	-8		-8	mA
loL	Low-level output current	70,	8		8	mA
Δt/Δν	Input transition rise or fall rate	Q	20		20	ns/V
TA	Operating free-air temperature	-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.

SN54AHCT16540, SN74AHCT16540 16-BIT BUFFERS/DRIVERS WITH 3-STATE OUTPUTS

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electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	T _A = 25°C			SN54AHCT16540		SN74AHCT16540		UNIT
TANAMETER	TEST CONDITIONS		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNII
Vou	I _{OH} = -50 μA	4.5 V	4.4	4.5		4.4		4.4		V
VOH	$I_{OH} = -8 \text{ mA}$	4.5 V	3.94			3.8		3.8		V
VOL	I _{OL} = 50 μA	4.5 V			0.1		0.1		0.1	V
VOL	$I_{OL} = 8 \text{ mA}$	4.5 V			0.36		0.44		0.44	V
lį	V _I = V _{CC} or GND	0 V to 5.5 V			±0.1		±1*		±1	μΑ
loz	$V_O = V_{CC}$ or GND	5.5 V			±0.25	4:	±2.5		±2.5	μΑ
Icc	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			4	372	40		40	μΑ
∆l _{CC} †	One input at 3.4 V, Other inputs at V _{CC} or GND	5.5 V			1.35	PRO.	1.5		1.5	mA
C _i	V _I = V _{CC} or GND	5 V		2	10				10	pF
Co	$V_O = V_{CC}$ or GND	5 V		3						pF

^{*} On products compliant to MIL-PRF-38535, this parameter is not production tested at $V_{CC} = 0 \text{ V}$.

switching characteristics over recommended operating free-air temperature range, V_{CC} = 5 V \pm 0.5 V (unless otherwise noted) (see Figure 1)

DADAMETED	PARAMETER FROM TO LOAD		TO LOAD T _A = 25°C)	SN54AHCT16540		SN74AHCT16540		UNIT		
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT	
t _{PLH}	А	Y	C _I = 15 pF		4**	8.5**	1**	10**	1	9.5	ns	
^t PHL	Α	ľ	OL = 13 pr		4**	8.5**	1**	10**	1	9.5	115	
^t PZH	ŌĒ	Υ	C _L = 15 pF		5.5**	10.4**	1**	12**	1	12	ns	
t _{PZL}	OE	Ĭ	CL = 15 pr		5.5**	10.4**	1**	12**	1	12	115	
t _{PHZ}	ŌĒ	Y	C _I = 15 pF		5**	10.4**	1**	12**	1	12	ns	
tPLZ	OE		T CL=1	CL = 13 pr		5**	10.4**	1**	12**	1	12	113
tPLH	Α	V	Y	C _I = 50 pF		6	9.5	1**	11**	1	10.5	ns
t _{PHL}	ζ	!	OL = 30 pr		6	9.5	$\eta_{\rm G}$	11	1	10.5	115	
^t PZH		Υ	C _I = 50 pF		7.5	11.4	0/1	13	1	13	ns	
tPZL	ŌĒ	Ĭ	CL = 50 pr		7.5	11.4	1	13	1	13	115	
t _{PHZ}	<u> </u>	<u>OE</u> Y C _L = 50 p	OF V C: - 50 pF	C 50 pE		8	11.4	1	13	1	13	ns
t _{PLZ}			CL = 30 pr		8	11.4	1	13	1	13	115	
tsk(o)			C _L = 50 pF			1***				1	ns	

^{**} On products compliant to MIL-PRF-38535, this parameter is not production tested.

noise characteristics, $V_{CC} = 5 \text{ V}$, $C_L = 50 \text{ pF}$, $T_A = 25^{\circ}\text{C}$ (see Note 4)

	PARAMETER		SN74AHCT16540		
	PARAWIETER	MIN	TYP	MAX	UNIT
V _{OL(P)}	Quiet output, maximum dynamic V _{OL}		0.7		V
V _{OL(V)}	Quiet output, minimum dynamic V _{OL}		-0.3		V
V _{OH(V)}	Quiet output, minimum dynamic V _{OH}		4.5		V
V _{IH(D)}	High-level dynamic input voltage	2			V
V _{IL(D)}	Low-level dynamic input voltage			0.8	V

NOTE 4: Characteristics are for surface-mount packages only.



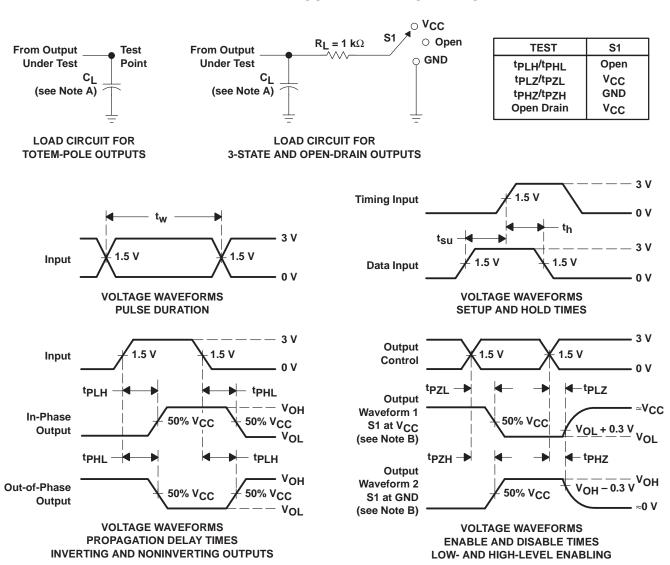
[†] This is the increase in supply current for each input at one of the specified TTL voltage levels rather than 0 V or V_{CC}.

^{***} On products compliant to MIL-PRF-38535, this parameter does not apply.

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$

PARAMETER	TEST CONDITIONS	TYP	UNIT
C _{pd} Power dissipation capacitance	No load, f = 1 MHz	14	pF

PARAMETER MEASUREMENT INFORMATION



- NOTES: A. C_L includes probe and jig capacitance.
 - B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 - C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq$ 3 ns. $t_f \leq$ 3 ns.
 - D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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